

Date:- 23 Jul, 2004

Data Sheet Issue:- 1

Fast Recovery Diode Type M2408N#020 to M2408N#060 Old Type No.: SM02-06CXC504

Absolute Maximum Ratings

	VOLTAGE RATINGS	MAXIMUM LIMITS	UNITS
V _{RRM}	Repetitive peak reverse voltage, (note 1)	200-600	V
V _{RSM}	Non-repetitive peak reverse voltage, (note 1)	300-700	V

	OTHER RATINGS	MAXIMUM LIMITS	UNITS
I _{F(AV)M}	Maximum average forward current, T _{sink} =55°C, (note 2)	2408	А
I _{F(AV)M}	Maximum average forward current. T _{sink} =100°C, (note 2)	1497	А
I _{F(AV)M}	Maximum average forward. T _{sink} =100°C, (note 3)	857	А
I _{F(RMS)}	Nominal RMS forward current, T _{sink} =25°C, (note 2)	4585	А
I _{F(d.c.)}	D.C. forward current, T _{sink} =25°C, (note 4)	3736	А
I _{FSM}	Peak non-repetitive surge $t_p=10ms$, $V_{RM}=60\%V_{RRM}$, (note 5)	24.0	kA
I _{FSM2}	Peak non-repetitive surge $t_p=10$ ms, $V_{RM} \le 10V$, (note 5)	26.4	kA
l ² t	$I^{2}t$ capacity for fusing t _p =10ms, V _{RM} =60%V _{RRM} , (note 5)	2.88×10 ⁶	A ² s
l ² t	$I^{2}t$ capacity for fusing t _p =10ms, V _{RM} ≤10V, (note 5)	3.48×10 ⁶	A ² s
T _{j op}	Operating temperature range	-40 to +150	°C
T _{stg}	Storage temperature range	-40 to +150	°C

Notes:-

1) De-rating factor of 0.13% per °C is applicable for T_j below 25°C.

2) Double side cooled, single phase; 50Hz, 180° half-sinewave.

3) Single side cooled, single phase; 50Hz, 180° half-sinewave.

4) Double side cooled.

5) Half-sinewave, $150^{\circ}C T_{j}$ initial.

Characteristics

	PARAMETER	MIN.	TYP.	MAX.	TEST CONDITIONS (Note 1)	UNITS	
V	Maximum pack forward voltage	-	-	1.45	I _{FM} =3000A	V	
V _{FM}	Maximum peak forward voltage	-	-	1.70	I _{FM} =4800A	v	
V _{T0}	Threshold voltage	-	-	1.065		V	
r _T	Slope resistance	-	-	0.122		mΩ	
		-	-	5	di/dt = 1000A/µs, 25°C		
V _{FRM}	Maximum forward recovery voltage	-	-	8	di/dt = 1000A/µs	V	
I _{RRM}	Peak reverse current	-	-	50	Rated V _{RRM}	mA	
Q _{rr}	Recovered charge	-	250	-		μC	
Q _{ra}	Recovered charge, 50% Chord	-	160	190	I _{FM} =1000A, t _p =1000µs, di/dt=200A/µs,	μC	
I _{rm}	Reverse recovery current	-	170	-	V _r =50V, 50% Chord.	А	
t _{rr}	Reverse recovery time, 50% Chord	-	1.9	-		μs	
P The second in the	Thermal resistance, innetice to be stainly	-	-	0.022	Double side cooled	K/W	
$R_{_{thJK}}$	Thermal resistance, junction to heatsink	-	-	0.044	Single side cooled		
F	Mounting force	19	-	26		kN	
	Mainta (-	480	-	Housing option NC and NT		
Wt	V _t Weight		360	-	Housing option ND	g	

Notes:-

1) Unless otherwise indicated $T_i=150$ °C.

Notes on rupture rated packages. This product is available with a non-rupture rated package. For additional details on these products, please consult factory.

Notes on Ratings and Characteristics

1.0 Voltage Grade Table

Voltage Grade	V _{RRM} (V)	V _{RSM} (V)	V _R dc (V)
02	200	300	140
04	400	500	260
06	600	700	420

2.0 De-rating Factor

A blocking voltage de-rating factor of 0.13% per °C is applicable to this device for T_i below 25°C.

3.0 ABCD Constants

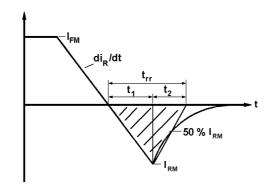
These constants (applicable only over current range of V_F characteristic in Figure 1) are the coefficients of the expression for the forward characteristic given below:

$$V_F = A + B \cdot \ln(I_F) + C \cdot I_F + D \cdot \sqrt{I_F}$$

where I_F = instantaneous forward current.

4.0 Reverse recovery ratings

(i) Q_{ra} is based on 50% I_{rm} chord as shown in Fig.(a) below.



(ii) Q_{rr} is based on a 150µs integration time.

I.e.
$$Q_{rr} = \int_{0}^{150 \mu s} i_{rr} . dt$$

(iii)

$$K Factor = \frac{t_1}{t_2}$$

5.0 Reverse Recovery Loss

The following procedure is recommended for use where it is necessary to include reverse recovery loss.

From waveforms of recovery current obtained from a high frequency shunt (see Note 1) and reverse voltage present during recovery, an instantaneous reverse recovery loss waveform must be constructed. Let the area under this waveform be E joules per pulse. A new sink temperature can then be evaluated from:

$$T_{SINK} = T_{J(MAX)} - E \cdot \left[k + f \cdot R_{thJK}\right]$$

Where k = 0.2314 (°C/W)/s

E = Area under reverse loss waveform per pulse in joules (W.s.)

f = Rated frequency in Hz at the original sink temperature.

 $R_{th,IK}$ = d.c. thermal resistance (°C/W)

The total dissipation is now given by:

$$W_{(tot)} = W_{(original)} + E \cdot f$$

NOTE 1 - Reverse Recovery Loss by Measurement

This device has a low reverse recovered charge and peak reverse recovery current. When measuring the charge, care must be taken to ensure that:

(a) AC coupled devices such as current transformers are not affected by prior passage of high amplitude forward current.

(b) A suitable, polarised, clipping circuit must be connected to the input of the measuring oscilloscope to avoid overloading the internal amplifiers by the relatively high amplitude forward current signal.

(c) Measurement of reverse recovery waveform should be carried out with an appropriate critically damped snubber, connected across diode anode to cathode. The formula used for the calculation of this snubber is shown below:

$$R^2 = 4 \cdot \frac{V_r}{C_s \cdot \frac{di}{dt}}$$

Where: V_r = Commutating source voltage

 C_{S} = Snubber capacitance

R = Snubber resistance

6.0 Snubber Components

When selecting snubber components, care must be taken not to use excessively large values of snubber capacitor or excessively small values of snubber resistor. Such excessive component values may lead to device damage due to the large resultant values of snubber discharge current. If required, please consult the factory for assistance.

7.0 Computer Modelling Parameters

7.1 Device Dissipation Calculations

$$I_{AV} = \frac{-V_{T0} + \sqrt{V_{T0} + 4 \cdot ff^{2} \cdot r_{T} \cdot W_{AV}}}{2 \cdot ff^{2} \cdot r_{T}}$$

Where $V_{T0} = 1.065$ V, $r_T = 0.122$ m Ω

ff = form factor (normally unity for fast diode applications)

$$W_{AV} = \frac{\Delta T}{R_{th}}$$
$$\Delta T = T_{j(MAX)} - T_{K}$$

7.2 Calculation of V_F using ABCD Coefficients

The forward characteristic I_F Vs V_F, on page 6 is represented in two ways;

- the well established V_{T0} and r_T tangent used for rating purposes and (i)
- (ii) a set of constants A, B, C, and D forming the coefficients of the representative equation for V_F in terms of I_F given below:

$$V_F = A + B \cdot \ln(I_F) + C \cdot I_F + D \cdot \sqrt{I_F}$$

The constants, derived by curve fitting software, are given in this report for both hot and cold characteristics. The resulting values for V_F agree with the true device characteristic over a current range, which is limited to that plotted.

	25°C Coefficients	150°C Coefficients
А	0.4179024	0.103541587
В	0.09763557	0.098139
С	5.3723×10 ⁻⁵	3.95463×10 ⁻⁵
D	3.45472×10 ⁻³	8.071285×10 ⁻³

8.0 Frequency Ratings

The curves illustrated in figures 8 to 16 are for guidance only and are superseded by the maximum ratings shown on page 1.

9.0 Square wave ratings

These ratings are given for load component rate of rise of forward current of 100 and 500 A/µs.

10.0 Duty cycle lines

The 100% duty cycle is represented on all the ratings by a straight line. Other duties can be included as parallel to the first.

150°C

25°C

10000

Curves

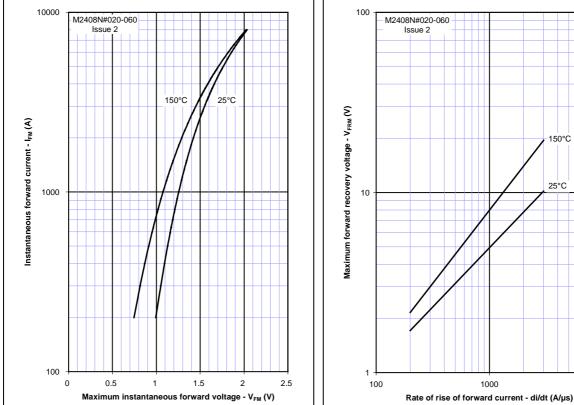
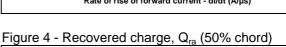
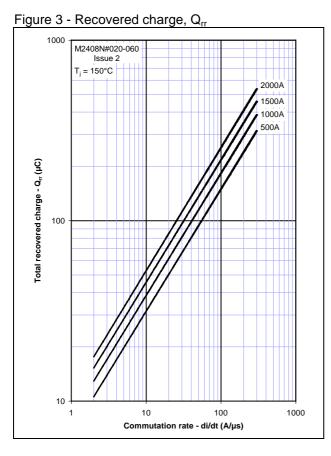
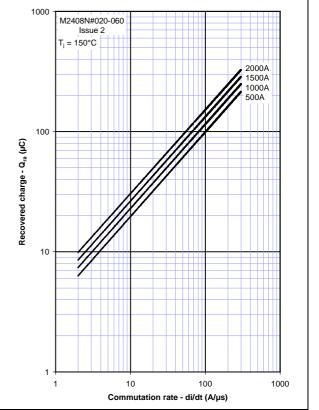


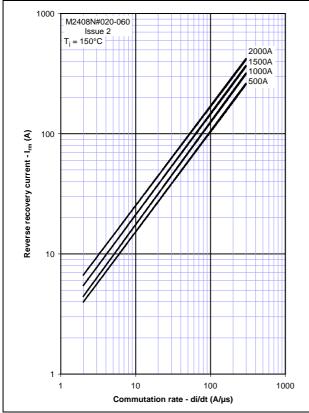
Figure 1 - Forward characteristics of Limit device

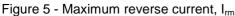
Figure 2 – Maximum forward recovery voltage

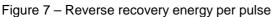


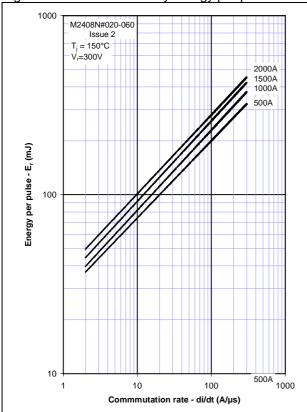


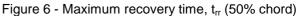












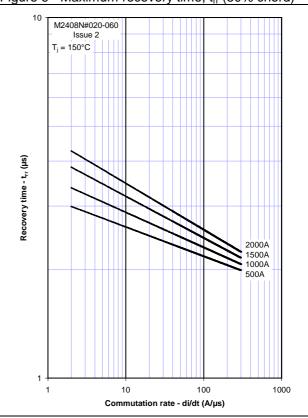
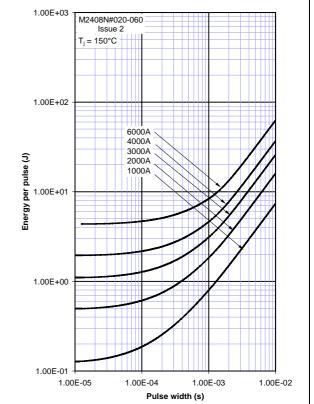
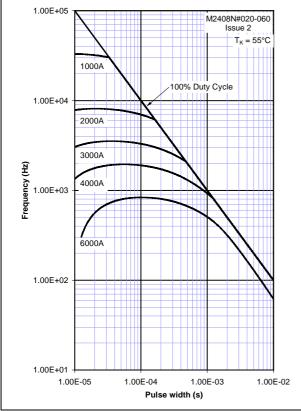
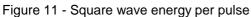


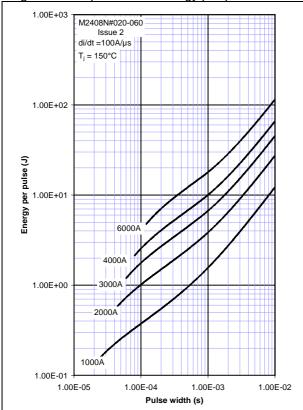
Figure 8 - Sine wave energy per pulse











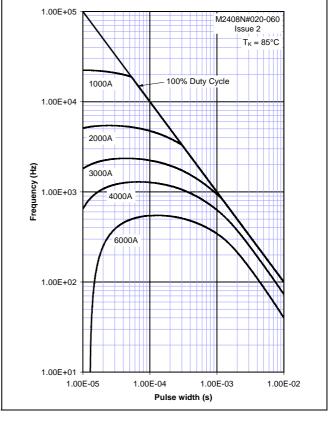


Figure 12 - Square wave energy per pulse

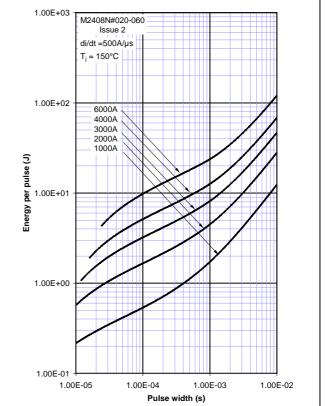
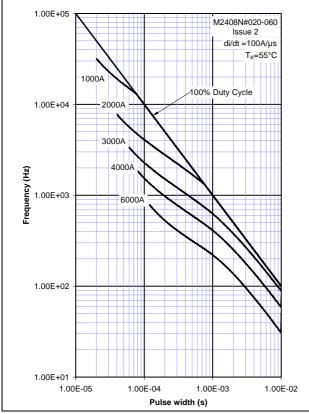
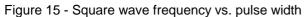
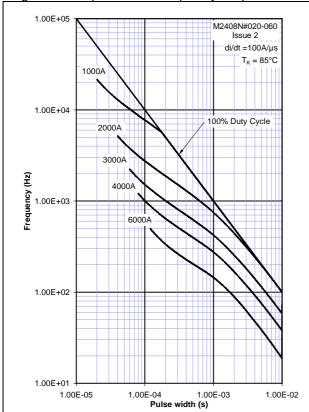


Figure 10 - Sine wave frequency vs. pulse width









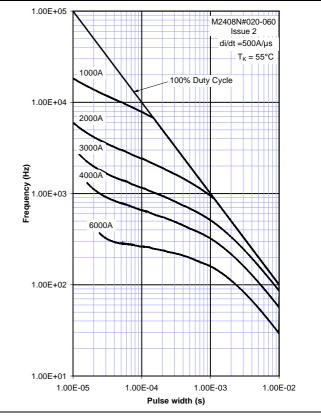


Figure 16 - Square wave frequency vs. pulse width

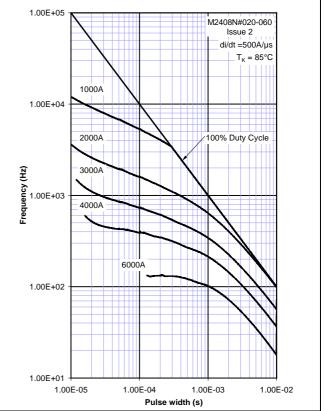


Figure 14 - Square wave frequency vs. pulse width

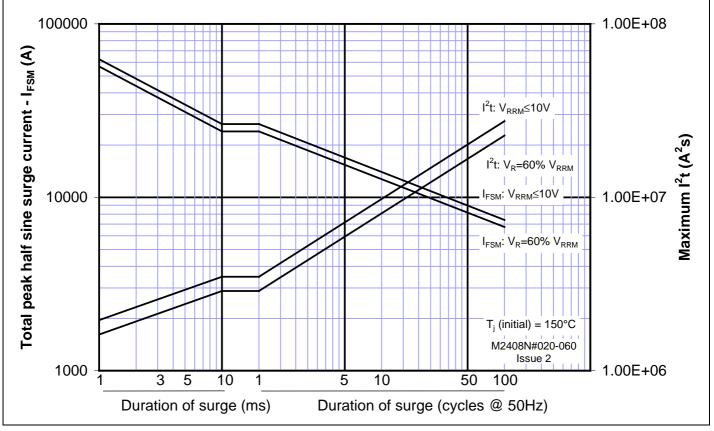
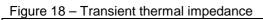
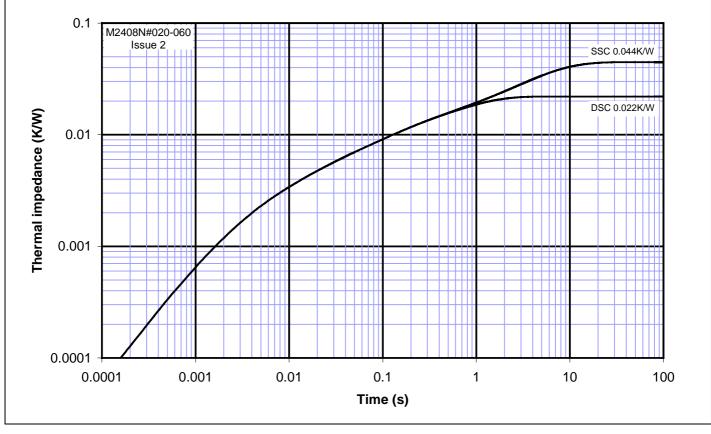


Figure 17 – Maximum surge and I²t ratings





Outline Drawing & Ordering Information

